

INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. 52433/754	U.S. SERIAL NO. <i>To Be Assigned</i>
	APPLICANT H. OHISHI, et al.	10/827,515 <i>AUT 412</i>

U. S. PATENT DOCUMENTS

Dates: April 19, 2004

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE
SSF	4,476,274	October 9, 1984	LIU	524	445	
OSP	5,539,018	July 23, 1996	LUHMANN et al.	523	201	
SSF	4,607,075	August 19, 1986	BÄUM et al.	524	449	
SDF	5,237,004	August 17, 1993	WU et al.	525	85	
SSF	4,219,628	August 26, 1980	WEEMES et al.	525	166	
SSF	4,629,750	December 16, 1986	HEPP	523	201	
SSF	4,659,767	April 21, 1987	DUNKLE et al.	524	504	
SSF	4,096,202	June 20, 1978	FARNHAM et al.	260	873	

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
SSF	0 256 391	February 24, 1988	EPO			English	
SSF	0 180 472	May 7, 1986	EPO			English	
SSF	0 472 418	February 26, 1992	EPO			English	
SSF	0 388 388	September 19, 1990	EPO			English	
SSF	0 653 461	May 17, 1995	EPO			English	
SSF	8-1864	January 9, 1996	Japan			Abstract	
SSF	62-91573	April 27, 1987	Japan			Abstract	
SSF	60-52179	January 18, 1985	Japan			Abstract	
	59-30743	July 28, 1984	Japan			No	
	3-269074	November 29, 1991	Japan			No	
	7-195617	August 1, 1995	Japan			No	
	7-290643	November 7, 1995	Japan			No	
	7-290644	November 7, 1995	Japan			No	
	58-17148	February 1, 1983	Japan			No	
	5-186613	July 27, 1993	Japan			No	
	60-12233	March 30, 1985	Japan			No	
	63-13829	March 28, 1988	Japan			No	

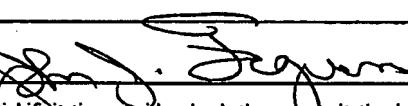
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61-149341	July 8, 1986	Japan		No
Z-9933	March 6, 1990	Japan		No
Z-57399	February 27, 1990	Japan		No
64-22530	January 25, 1989	Japan		No

OTHER DOCUMENTS

EXAMINER INITIAL	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
JSF	Journal Of Polymer Science Part A Polymer Chemistry, Vol. 31, pp 435-441, 1993, T.O. AHN et al.
JSF	Patent Abstracts Of Japan, JP 53-081530, 7/19/78
JSF	Patent Abstracts Of Japan, JP 06-159653, 6/20/94 (Pub: SP 08 - 001864 9/1/92) JSF 8/4/07
EXAMINER 	DATE CONSIDERED 7/6/2000
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	